

6ED2230S12T

1200 V Three Phase Gate Driver with Integrated Bootstrap Diode and OCP

Features

- Infineon Thin-Film-SOI technology
- Fully operational to +1200 V
- Integrated Ultra-fast Bootstrap Diode
- Floating channel designed for bootstrap operation
- Output source/sink current capability +0.35 A/-0.65 A
- Tolerant to negative transient voltage up to -100 V (Pulse width is up 700 ns) given by SOI-technology
- Undervoltage lockout for both channels
- 3.3 V, 5 V, and 15 V input logic compatible
- Over current protection with $\pm 5\%$ ITRIP threshold
- Fault reporting, automatic Fault clear and Enable function on the same pin (RFE)
- Matched propagation delay for all channels
- Integrated 460 ns deadtime protection
- Shoot-through (cross-conduction) protection

Product summary

- V_{OFFSET} $\leq 1200 \text{ V}$
- V_{CC} $= 13 \text{ V} - 20 \text{ V}$
- $I_{\text{O+/- (typ.)}}$ $= 0.35 \text{ A}/0.65 \text{ A}$
- $t_{\text{on/off (typ.)}}$ $= 700 \text{ ns}/650 \text{ ns}$
- Deadtime (typ.) $= 460 \text{ ns}$

Package



DSO-24 (DSO-28 with 4 pins removed)

Typical applications

- Industrial Drives
- Embedded inverters for Motor Control in Pumps, Fans.
- Commercial and Lite Commercial Air Conditioning

Description

The 6ED2230S12T is a high voltage, high speed IGBT with three independent high side and low side referenced output channels for three phase applications. Proprietary HVIC and latch immune CMOS technologies enable ruggedized monolithic construction. The logic input is compatible with standard CMOS or TTL outputs, down to 3.3 V logic. An over-current protection (OCP) function which terminates all six outputs can also be derived from this resistor. An open drain FAULT signal is provided to indicate that an over-current or undervoltage shutdown has occurred. Fault conditions are cleared automatically after a delay programmed externally via an RC network. The output drivers feature a high-pulse current buffer stage designed for minimum driver cross-conduction. The floating channel can be used to drive N-channel power MOSFETs or IGBTs in the high side configuration which operates up to 1200 V. Propagation delays are matched to simplify the HVIC's use in high frequency applications.

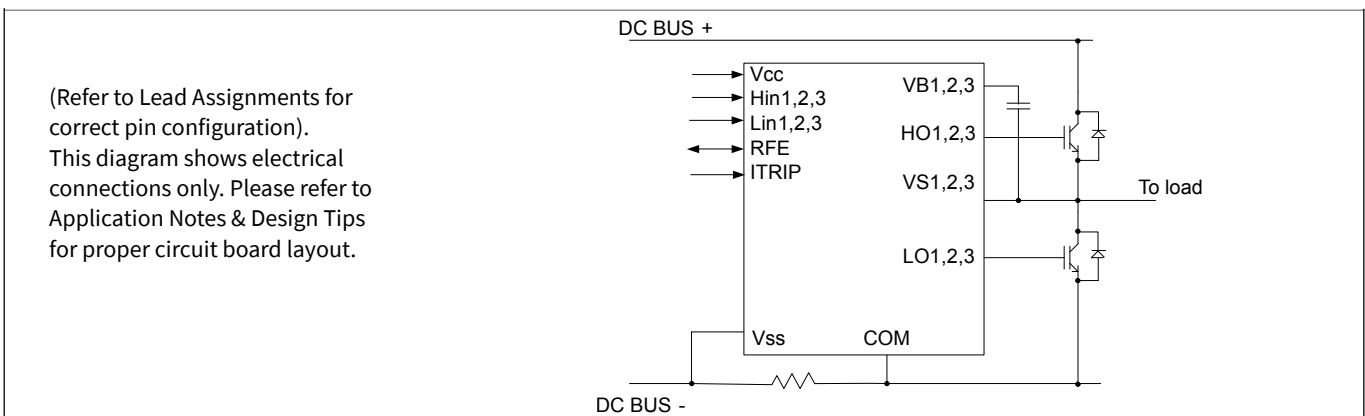


Figure 1 Typical connection diagram

6ED2230S12T

1200 V Three Phase Gate Driver with Integrated Bootstrap Diode and OCP



Device information

Device information

Base part number	Package type	Standard pack		Orderable part number
		Form	Quantity	
6ED2230S12T ¹⁾	DSO-24	Tape and Reel	1000	6ED2230S12TXUMA1

¹ Also available for die sales as 'Sawn Wafer on Film' with part number 6ED2230S12C. Please contact Infineon for more information.

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Block diagram

1 Block diagram

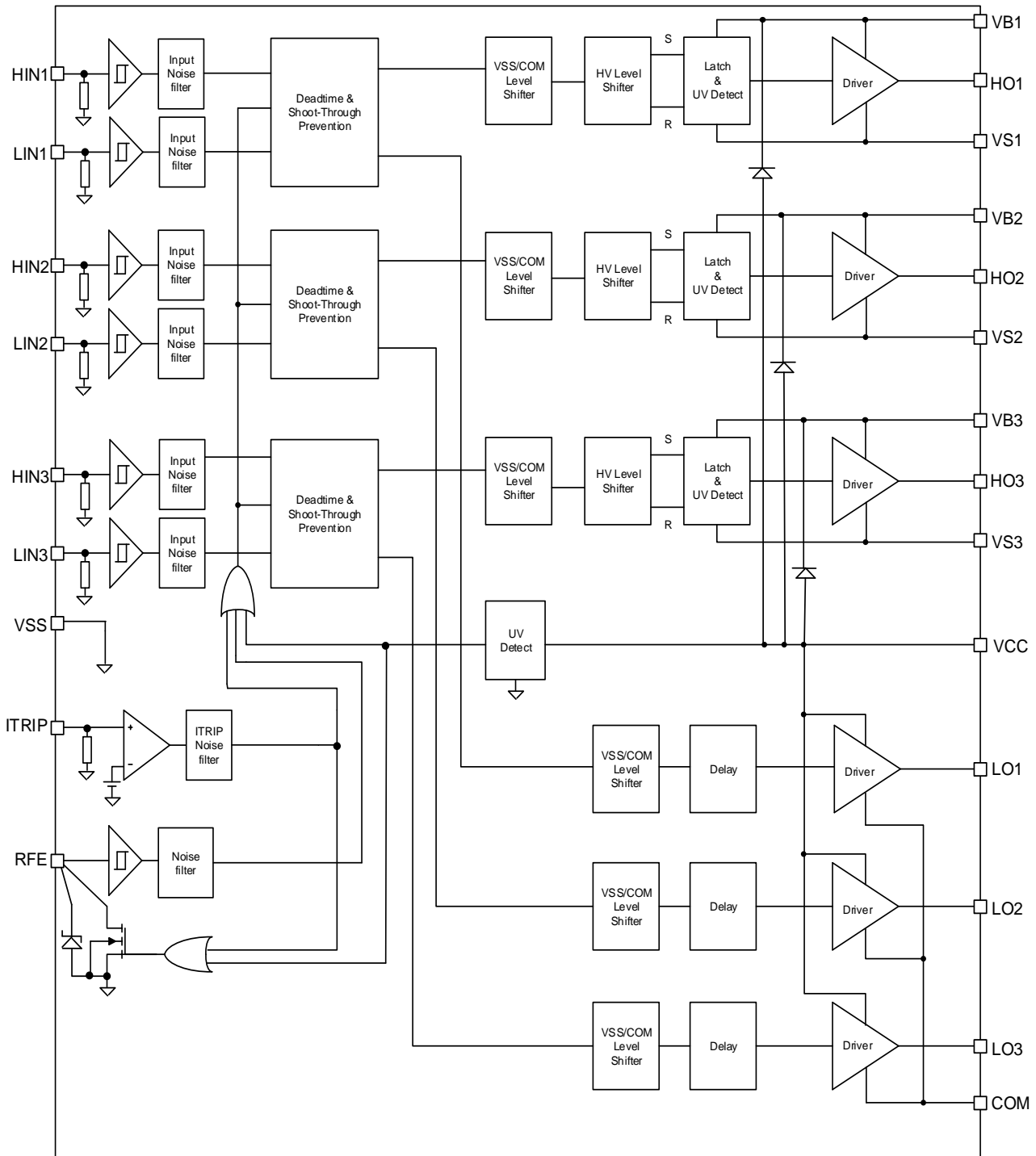


Figure 2 Functional block diagram

Lead configuration

2 Lead configuration

Table 1 Lead definitions

Symbol	Description
<i>HIN</i> _{1,2,3}	Logic input for high side gate driver output (HO), in phase
<i>LIN</i> _{1,2,3}	Logic input for low side gate driver output (LO), in phase
<i>V_B</i> _{1,2,3}	High side floating supply
<i>HO</i> _{1,2,3}	High side gate drive output
<i>V_S</i> _{1,2,3}	High side floating supply return
<i>V_{CC}</i>	Low side and logic fixed supply
<i>LO</i>	Low side gate drive output
<i>COM</i>	Low side return
<i>V_{SS}</i>	Logic ground
<i>ITRIP</i>	Analog input for over-current shutdown. When active, ITRIP shuts down outputs and activates RFE low. When ITRIP becomes inactive, RFE stays active low for an externally set time t _{FLTCLR} , then automatically becomes inactive (open-drain high impedance).
<i>RFE</i>	Integrated fault reporting function like over-current (ITRIP), or low-side undervoltage lockout and the fault clear timer. This pin has negative logic and an open-drain output. The use of over-current protection requires the use of external components.

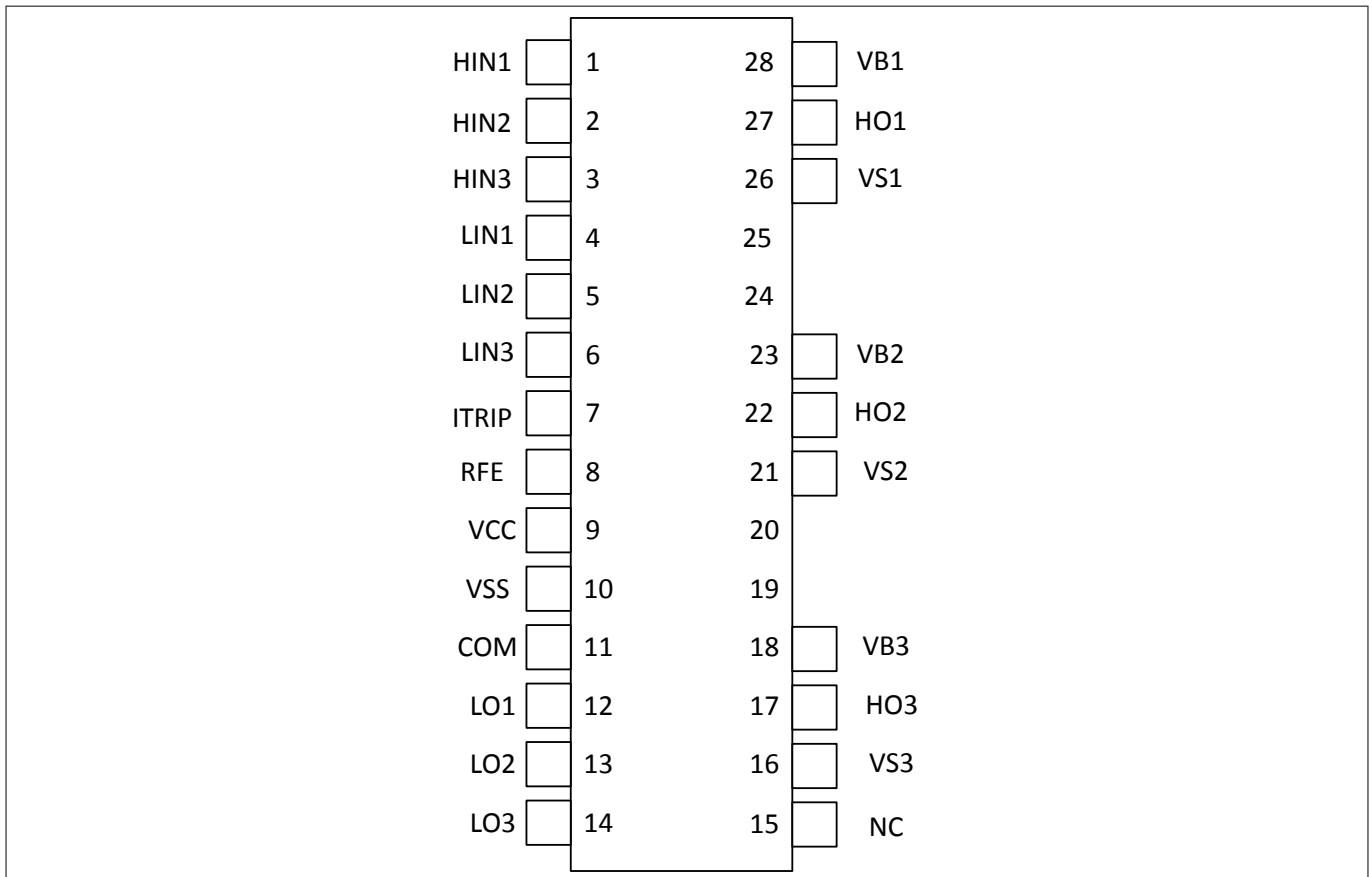


Figure 3 Lead Assignments

Absolute maximum ratings

3 Absolute maximum ratings

Table 2 Absolute maximum ratings

Absolute maximum ratings indicate sustained limits beyond which damage to the device may occur. All voltage parameters are absolute voltages referenced to COM unless otherwise stated in the table. The thermal resistance and power dissipation ratings are measured under board mounted and still air conditions.

Parameter	Symbol	Values		Unit	Note or Test Condition
		Min.	Max.		
Low side supply voltage	V_{CC}	-0.3	25	V	—
Logic input voltage (LIN, HIN, RFE, ITRIP)	V_{IN}	$V_{SS} - 5$	$V_{CC} + 0.3$	V	—
High-side floating well supply voltage	$V_{B1,2,3}$	-0.3	1225	V	—
High-side floating well supply return voltage	$V_{S1,2,3}$	$V_{B1,2,3} - 25$	$V_{B1,2,3} + 0.3$	V	—
Floating gate drive output voltage	$V_{HO1,2,3}$	$V_{S1,2,3} - 0.3$	$V_{B1,2,3} + 0.3$	V	—
Low-side output voltage	$V_{LO1,2,3}$	- 0.3	$V_{CC} + 0.3$	V	—
Logic ground	V_{SS}	$V_{CC} - 25$	$V_{CC} + 0.3$	V	—
Allowable VS offset supply transient relative to COM	dV_S/dt	—	50	V/ns	—
Package power dissipation	P_D	—	1.3	W	$T_A + 25^\circ\text{C}$
Thermal resistance, junction to ambient	R_{thJA}	—	75	$^\circ\text{C}/\text{W}$	—
Junction temperature	T_J	—	150	$^\circ\text{C}$	—
Storage temperature	T_S	-55	150	$^\circ\text{C}$	—
Lead temperature (soldering, 10 seconds)	T_L	—	300	$^\circ\text{C}$	—

Recommended operating conditions

4 Recommended operating conditions

Table 3 Recommended operating conditions

For proper operation, the device should be used within the recommended conditions. All voltage parameters are absolute voltages referenced to COM unless otherwise stated in the table. The offset rating is tested with supplies of $(V_{CC} - COM) = (V_B - V_S) = 15\text{ V}$.

Parameter	Symbol	Values		Unit	Note or Test Condition
		Min.	Max.		
Low-side supply voltage	V_{CC}	1	20	V	—
Logic input voltage (LIN, HIN, ITRIP)	V_{IN}	VSS	VSS + 5	V	—
RFE logic input voltage	V_{RFE}	VSS	VCC	V	—
High-side floating well supply voltage	$V_{B1,2,3}$	VS1,2,3 + 12	VS1,2,3 + 20	V	—
High-side floating well supply offset voltage	$V_{S1,2,3}$	COM - 8	900	V	1)
Transient High-side floating well supply offset voltage	V_{St}	-100	1000	V	2)
Floating gate drive output voltage	$V_{HO1,2,3}$	VS1,2,3	VB1,2,3	V	—
Low-side output voltage	$V_{LO1,2,3}$	0	VCC	V	—
Logic ground	V_{SS}	-5	5	V	—
Ambient temperature	T_A	-40	125	°C	—

1 Logic operation for VS of -8 V to 1200 V. Logic state held for Vs of -8 V to -V_{BS}

2 In case VCC > VB there is an additional power dissipation in the internal bootstrap diode between pins VCC and VBx. Insensitivity of bridge output to negative transient voltage up to -100 V is not subject to production test – verified by design / characterization.

Electrical characteristics

5 Electrical characteristics

5.1 Static electrical characteristics

Table 4 Static electrical characteristics

(VCC - COM) = (VB - VS) = 15 V. TA = 25 °C unless otherwise specified. The VIN and IIN parameters are referenced to COM. The VO and IO parameters are referenced to respective VS and COM and are applicable to the respective output leads HO or LO. The VCCUV parameters are referenced to COM. The VBSUV parameters are referenced to VS.

Parameter	Symbol	Values			Unit	Note or Test Condition
		Min.	Typ.	Max.		
V _{BS} supply under voltage positive threshold	V _{BSUV+}	9.2	10.4	11.6	V	—
V _{BS} supply under voltage negative threshold	V _{BSUV-}	8.3	9.4	10.5	V	—
V _{BS} supply under voltage hysteresis	V _{BSUVHY}	—	1	—	V	—
V _{CC} supply under voltage positive threshold	V _{CCUV+}	10.2	11.4	12.6	V	—
V _{CC} supply under voltage negative threshold	V _{CCUV-}	9.3	10.4	11.5	V	—
V _{CC} supply under voltage hysteresis	V _{CCUVHY}	—	1	—	V	—
High level output voltage drop, V _{BIAS} -V _O	V _{OH}	—	0.35	—	V	I _o = 20 mA
Low level output voltage drop, V _O	V _{OL}	—	0.15	—	V	I _o = 20 mA
Logic “1” input voltage	V _{IH}	2.3	—	—	V	—
Logic “0” input voltage	V _{IL}	—	—	0.7	V	—
RFE positive going threshold	V _{RFE+}	1.7	1.9	2.3	V	—
RFE negative going threshold	V _{RFE-}	0.7	0.9	1.1	V	—
ITRIP positive going threshold	V _{ITRIP+}	0.475	0.500	0.525	V	—
ITRIP negative going threshold	V _{ITRIP-}	0.425	0.450	0.475	V	—
ITRIP hysteresis	V _{ITRIP HYS}	—	0.050	—	V	—
High-side floating well offset supply leakage	I _{LK}	—	—	50	μA	V _B = V _S = 1200 V
Quiescent V _{BS} supply current	I _{QBS}	—	175	250	μA	V _{IN} = 0 V or 5 V
Quiescent V _{CC} supply current	I _{QCC}	—	1000	1500	μA	V _{IN} = 0 V or 5 V
Mean output current for load capacity charging from 3 V (20%) to 6 V (40%)	I _{O+} mean	200	300	—	mA	C = 22 nF

Electrical characteristics

Table 4 Static electrical characteristics (continued)

(VCC - COM) = (VB - VS) = 15 V. TA = 25 °C unless otherwise specified. The VIN and IIN parameters are referenced to COM. The VO and IO parameters are referenced to respective VS and COM and are applicable to the respective output leads HO or LO. The VCCUV parameters are referenced to COM. The VBSUV parameters are referenced to VS.

Parameter	Symbol	Values			Unit	Note or Test Condition
		Min.	Typ.	Max.		
Mean output current for load capacity discharging from 10.5 V (70%) to 7.5 V (50%)	I_{O-mean}	400	600	—	mA	C = 22 nF
Output high short circuit pulsed current	I_{O+}	—	350	—	mA	$V_O = 0$ V PW ≤ 1 μs
Output low short circuit pulsed current	I_{O-}	—	650	—	mA	$V_O = 15$ V PW ≤ 1 μs
Logic “1” Input bias current (RFE)	I_{RFE+}	—	0	1	μA	$V_{RFE} = 3.3$ V
Logic “0” Input bias current (RFE)	I_{RFE-}	1	0	—	μA	$V_{RFE} = 0$ V
Logic “1” Input bias current (LIN, HIN)	I_{IN+}	—	1000	1250	μA	$V_{IN} = 5$ V
Logic “0” Input bias current (LIN, HIN)	I_{IN-}	—	—	1	μA	$V_{IN} = 0$ V
Logic “1” Input bias current (ITRIP)	I_{ITRIP+}	—	15	25	μA	$V_{IN} = 1$ V
Logic “0” Input bias current (ITRIP)	I_{ITRIP-}	—	—	1	μA	$V_{IN} = 0$ V
Bootstrap diode on resistance	R_{BS}	—	120	150	Ω	—
Bootstrap diode forward voltage drop	V_{FBSD}	—	0.9	—	V	$I_o = 0.3$ mA
RFE mos resistance	$R_{ON, RFE}$	—	40	60	Ω	—

Please refer to Application Section for integrated bootstrap diode description.

5.2 Dynamic electrical characteristics

Table 5 Dynamic electrical characteristics

$V_{CC} = V_B = 15$ V, $V_S = COM$, $T_A = 25$ °C, and $C_L = 1000$ pF unless otherwise specified.

Parameter	Symbol	Values			Unit	Note or Test Condition
		Min.	Typ.	Max.		
Turn-on propagation delay	t_{ON}	500	700	900	ns	
Turn-off propagation delay	t_{OFF}	450	650	850	ns	
Turn-on rise time	t_R	—	35	—	ns	

Electrical characteristics
Table 5 Dynamic electrical characteristics (continued)

$V_{CC} = V_B = 15\text{ V}$, $V_S = \text{COM}$, $T_A = 25\text{ }^\circ\text{C}$, and $C_L = 1000\text{ pF}$ unless otherwise specified.

Parameter	Symbol	Values			Unit	Note or Test Condition
		Min.	Typ.	Max.		
Turn-off fall time	t_F	—	20	—	ns	
Dead time, LO turn-off to HO turn-on & HO turn-off to LO turn-on	DT	300	460	700	ns	
Delay matching time (t_{ON} , t_{OFF})	MT	—	—	130	ns	
Enable low to output shutdown propagation delay	t_{EN}	—	600	—	ns	
Input filter time (LIN, HIN, EN)	$T_{FIL,IN}$	200	350	500	ns	
FAULT clear time ($R = 2\text{ M}\Omega$, $C = 1\text{ nF}$)	T_{FLTCLR}	—	1.9	—	ms	VDD = 3.3V
ITRIP to output shutdown propagation delay	T_{ITRIP}	—	750	1250	ns	$V_{ITRIP} = 1\text{ V}$
ITRIP blanking time	T_{BL}	—	500	—	ns	
ITRIP to FAULT propagation delay	T_{FLT}	450	650	900	ns	

Application information and additional details

6 Application information and additional details

Information regarding the following topics are included as subsections within this section of the datasheet.

- IGBT/MOSFET gate drive
- Switching and timing relationships
- Deadtime
- Matched propagation delays
- Input logic compatibility
- Undervoltage lockout protection
- Shoot-Through protection
- Enable input
- Fault reporting and programmable fault clear timer
- Over-Current protection
- Truth table: Undervoltage lockout, ITRIP, and ENABLE
- Advanced input filter
- Short-Pulse / Noise rejection
- Integrated bootstrap diodes
- Negative V_S transient SOA
- PCB layout tips
- Additional documentation

6.1 IGBT/MOSFET gate drive

The 6ED2230S12T HVICs are designed to drive MOSFET or IGBT power devices. [Figure 4](#) and [Figure 5](#) illustrate several parameters associated with the gate drive functionality of the HVIC. The output current of the HVIC, used to drive the gate of the power switch, is defined as I_{O+} . The voltage that drives the gate of the external power switch is defined as V_{HO} for the high-side power switch and V_{LO} for the low-side power switch; this parameter is sometimes generically called V_{OUT} and in this case does not differentiate between the high-side or low-side output voltage.

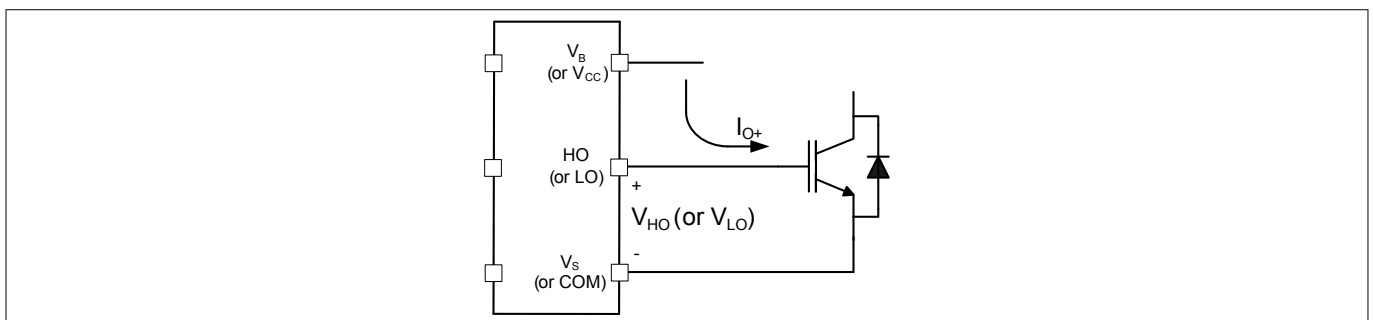


Figure 4 HVIC sourcing current

Application information and additional details

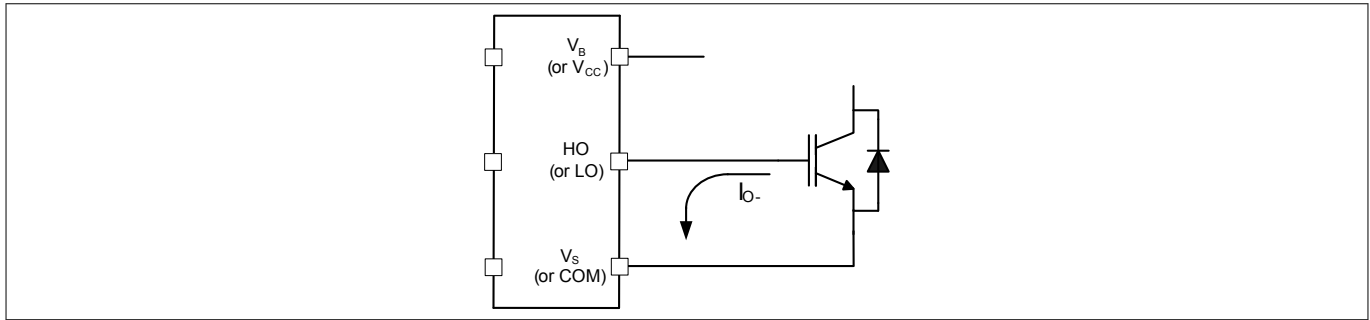


Figure 5 HVIC sinking current

6.2 Switching and timing relationships

The relationships between the input and output signals of the 6ED2230S12T are illustrated below in [Figure 6](#). From these figures, we can see the definitions of several timing parameters (i.e., PW_{IN} , PW_{OUT} , t_{ON} , t_{OFF} , t_R , and t_F) associated with this device.

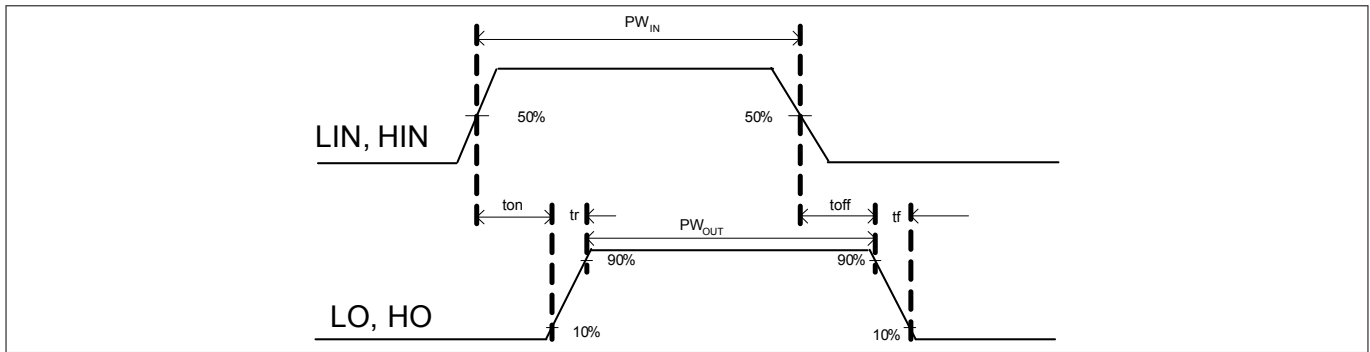


Figure 6 Switching time waveforms Input/output timing diagram

[Figure 7](#) and [Figure 8](#) illustrate the timing relationships of some of the functionality of the 6ED2230S12T; this functionality is described in further detail later in this document.

During interval A of [Figure 7](#), the HVIC has received the command to turn-on both the high- and low-side switches at the same time; as a result, the shoot-through protection of the HVIC has prevented this condition. HVIC is keeping on output channel that is already on ignoring the 2nd input signal.

Interval B of [Figure 7](#) and [Figure 8](#) shows that the signal on the ITRIP input pin has gone from a low to a high state; as a result, all of the gate drive outputs have been disabled (i.e., see that HO has returned to the low state; LO is also held low), and a fault condition is reported on the RFE pin, which goes 0V. Once the ITRIP input has returned to the low state, the output will remain disabled and the fault condition reported until the voltage on the RFE pin charges up to $VRFE+$ threshold; the charging characteristics are dictated by the RC network attached to the RFE pin. After fault clear time HVIC is waiting for a new input signal on LIN/HIN before activate the output stage (LO/HO).

During interval C of [Figure 7](#) and [Figure 9](#), we can see that the RFE pin has been pulled low (as is the case when the driver IC has received a command from the control IC to shutdown); these results in the outputs (HO and LO) being held in the low state until the RFE pin is pulled high. After an enable event HVIC will wait for a new input signal on LIN/HIN before activate the output stage (LO/HO).

Application information and additional details

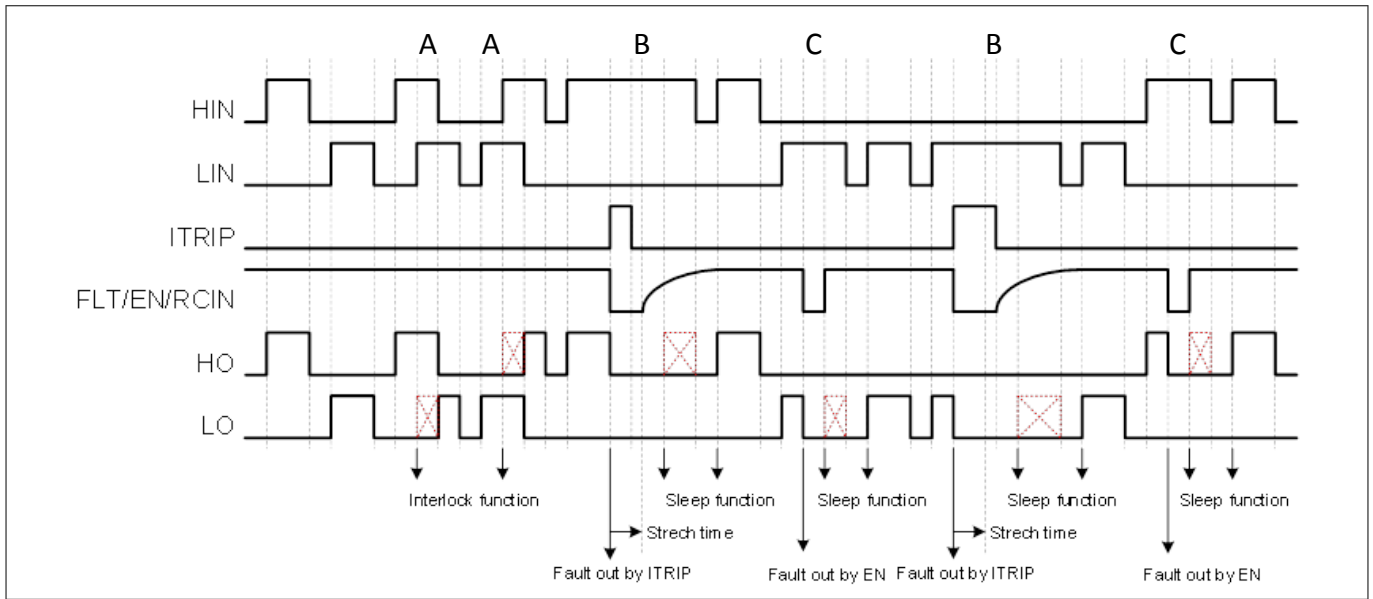


Figure 7 Input/output timing diagram

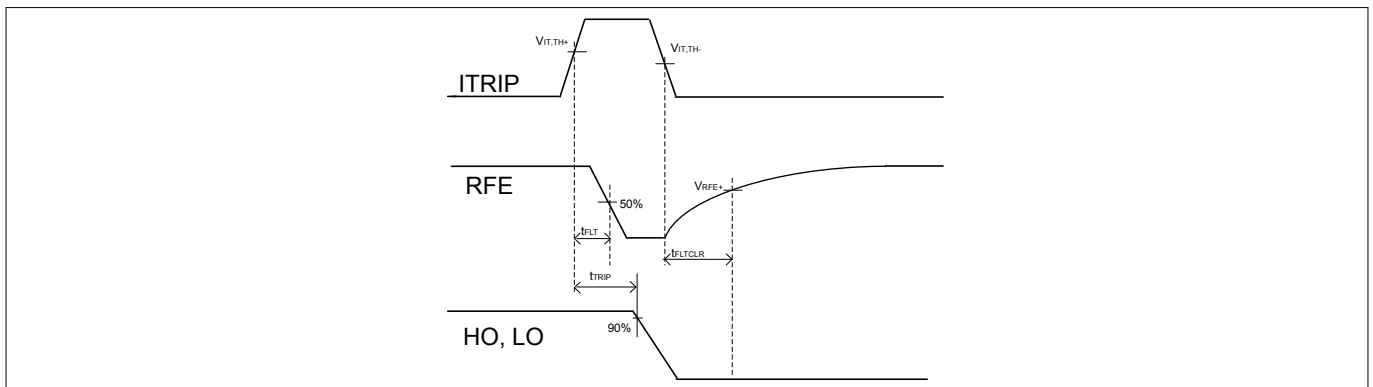


Figure 8 Detailed view of B interval

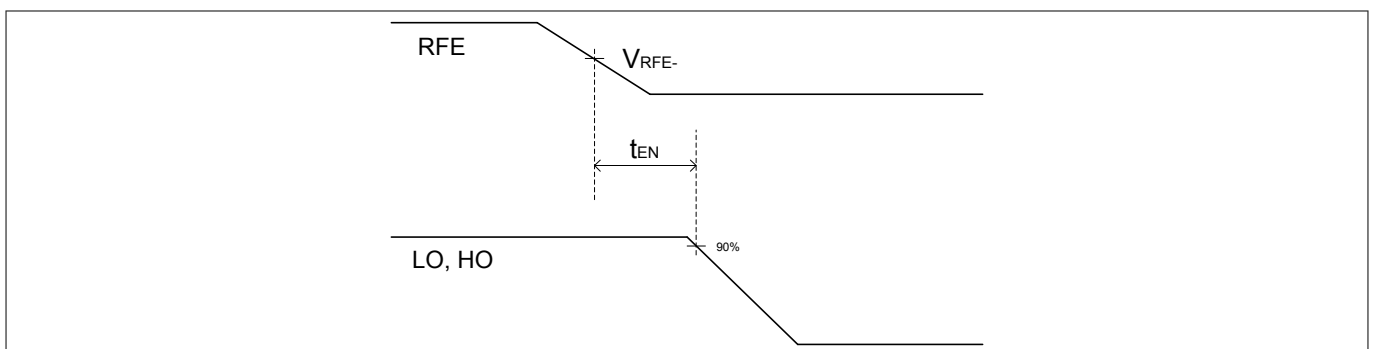


Figure 9 Detailed view of C interval

6.2.1 Deadtime

This HVIC features integrated deadtime protection circuitry. The deadtime for these ICs is fixed; other ICs within Infineon’s HVIC portfolio feature programmable deadtime for greater design flexibility. The deadtime feature inserts a time period (a minimum deadtime) in which both the high- and low-side power switches are held off; this is done to ensure that the power switch being turned off has fully turned off before the second power

Application information and additional details

switch is turned on. This minimum deadtime is automatically inserted whenever the external deadtime is shorter than DT; external deadtimes larger than DT are not modified by the gate driver.

6.2.2 Matched propagation delays

The 6ED2230S12T HVIC is designed with propagation delay matching circuitry. With this feature, the IC’s response at the output to a signal at the input requires approximately the same time duration (i.e., tON, tOFF) for both the low-side channels and the high-side channels; the maximum difference is specified by the delay matching parameter (MT). The propagation turn-on delay (tON) of the 6ED2230S12T is matched to the propagation turn-on delay (tOFF).

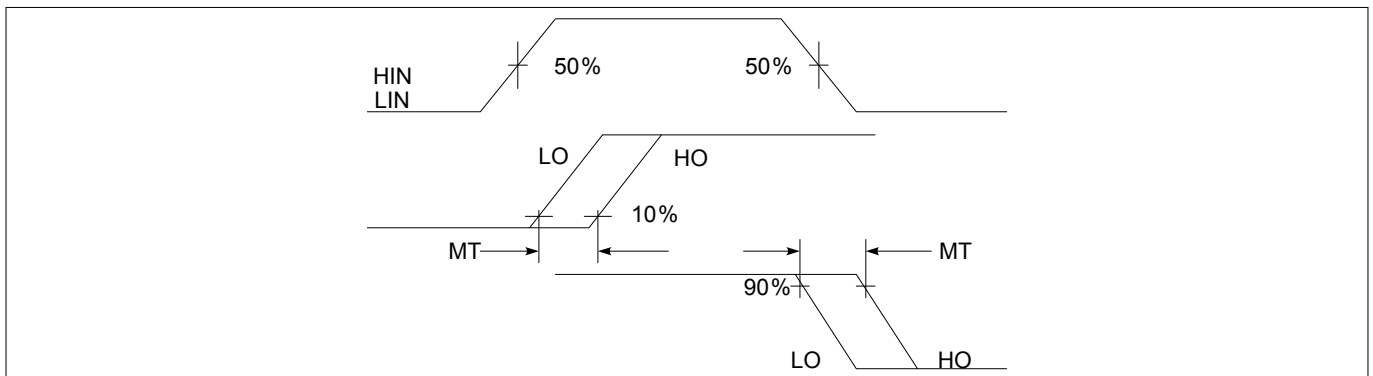


Figure 10 Delay Matching Waveform Definition

6.3 Input logic compatibility

The inputs of this IC are compatible with standard CMOS and TTL outputs. The 6ED2230S12T has been designed to be compatible with 3.3 V and 5 V logic-level signals. Figure 11 illustrates an input signal to the 6ED2230S12T, its input threshold values, and the logic state of the IC as a result of the input signal.

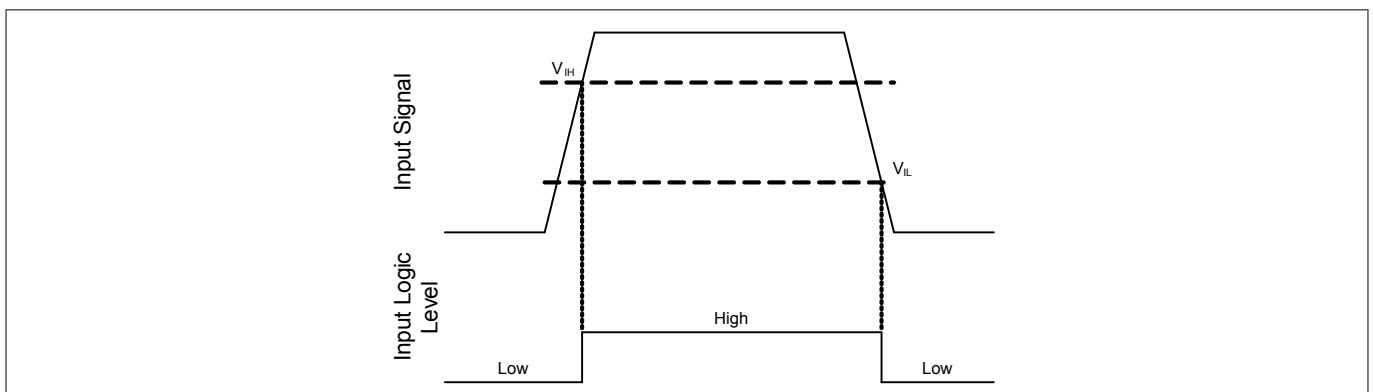


Figure 11 HIN & LIN input thresholds

6.4 Undervoltage lockout protection

This HVIC provides undervoltage lockout protection on both the VCC (logic and low-side circuitry) power supply and the VBS (high-side circuitry) power supply. Figure 12 is used to illustrate this concept; VCC (or VBS) is plotted over time and as the waveform crosses the UVLO threshold (VCCUV+/- or VBSUV+/-) the undervoltage protection is enabled or disabled.

Upon power-up, should the VCC voltage fail to reach the VCCUV+ threshold, the IC will not turn-on. Additionally, if the VCC voltage decreases below the VCCUV- threshold during operation, the undervoltage lockout circuitry

Application information and additional details

will recognize a fault condition and shutdown the high- and low-side gate drive outputs, and the FAULT pin will transition to the low state to inform the controller of the fault condition.

Upon power-up, should the VBS voltage fail to reach the VBSUV threshold, the IC will not turn-on. Additionally, if the VBS voltage decreases below the VBSUV threshold during operation, the undervoltage lockout circuitry will recognize a fault condition, and shutdown the high-side gate drive outputs of the IC.

The UVLO protection ensures that the IC drives the external power devices only when the gate supply voltage is sufficient to fully enhance the power devices. Without this feature, the gates of the external power switch could be driven with a low voltage, resulting in the power switch conducting current while the channel impedance is high; this could result in very high conduction losses within the power device and could lead to power device failure.

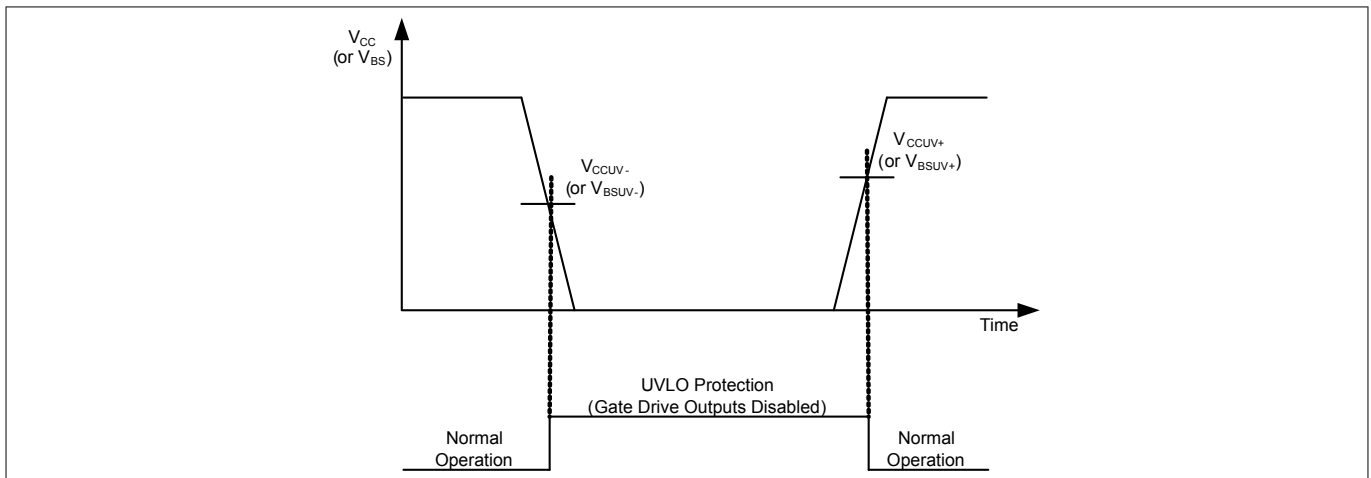


Figure 12 UVLO protection

6.5 Shoot-Through protection

The 6ED2230S12T is equipped with shoot-through protection circuitry (also known as cross-conduction prevention circuitry). **Figure 13** shows how this protection circuitry prevents both the high- and low-side switches from conducting at the same time.

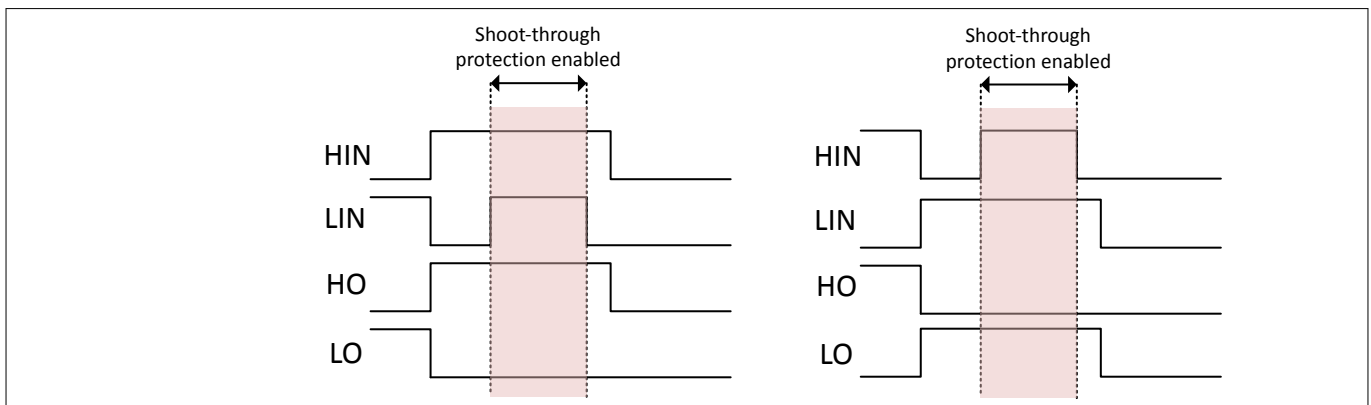


Figure 13 Illustration of shoot-through protection circuitry

6.6 Enable input

The 6ED2230S12T provides an enable functionality that allows it to shutdown or enable the HVIC. When the RFE pin is in the high state the HVIC is able to operate normally (assuming no other under voltage fault conditions on Vcc). When the RFE pin is in a low state, the gate drive outputs are pulled low until the enable condition is

Application information and additional details

restored. The enable circuitry of the 6ED2230S12T features an input filter; the minimum input duration is specified by tFIL, IN. Please refer to the RFE pin parameters VRFE+, VRFE-, and IRFE for the details of its use.

6.7 Fault reporting and programmable fault clear timer

The 6ED2230S12T provides an integrated fault reporting output and an adjustable fault clear timer. There are two situations that would cause the HVIC to report a fault via the RFE pin. The first is an undervoltage condition of VCC and the second is if the ITRIP pin recognizes a fault. Once the fault condition occurs, the RFE pin is internally pulled to Vss and the fault clear timer is activated. The RFE output stays in the low state until the fault condition has been removed and the fault clear timer expires; once the fault clear timer expires, the voltage on the RFE pin will return to its external pull-up voltage.

The length of the fault clear time period (tFLTCLR) is determined by a fix time constant added to exponential charging characteristics of the capacitor where the time constant is set by RRFE and CRFE. Figure 14 shows that RRFE is connected between the external supply (VDD) and the RFE pin, while CRFE is placed between the RFE and Vss pins.

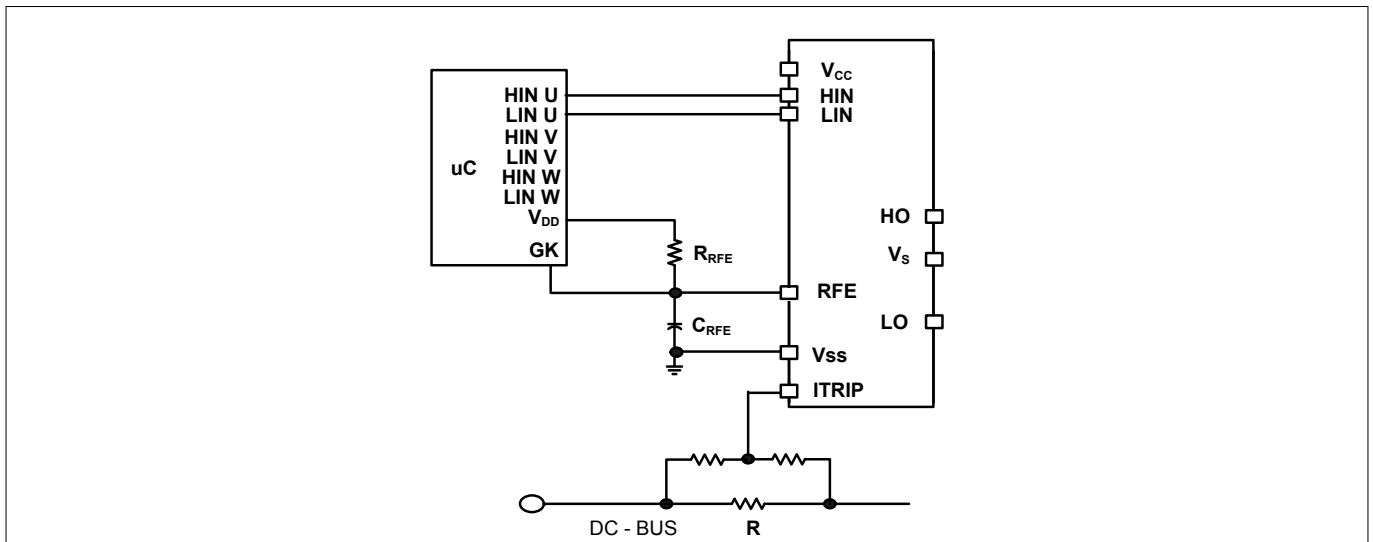


Figure 14 Programming the fault clear timer

The design guidelines for this network are shown in Table 6.

Table 6 Design guidelines

CRFE	≤1 nF
	Ceramic
RRFE	0.5 MΩ to 2 MΩ
	>> RON,REF

The length of the fault clear time period can be determined by using the formula below.

$$u_C(t) = V_f * (1 - e^{-t/RC})$$

$$t_{FLTCLR} = -(R_{RFE} * C_{RFE}) * \ln(1 - V_{RFE+} / V_{DD}) + 160 \mu s$$

The voltage on the RFE pin should not exceed the VDD of the uC power supply.

Application information and additional details

6.8 Over-Current protection

The 6ED2230S12T HVICs are equipped with an ITRIP input pin. This functionality can be used to detect over-current events in the DC- bus. Once the HVIC detects an over-current event through the ITRIP pin, the outputs are shutdown, and RFE is pulled to Vss.

The level of current at which the over-current protection is initiated is determined by the resistor network (i.e., R₀, R₁, and R₂) connected to ITRIP as shown in Figure 15, and the ITRIP threshold (V_{ITRIP+}). The circuit designer will need to determine the maximum allowable level of current in the DC- bus and select R₀, R₁, and R₂ such that the voltage at node V_x reaches the over-current threshold (V_{ITRIP+}) at that current level.

$$V_{ITRIP+} = R_0 \cdot I_{DC} \cdot (R_1 / (R_1 + R_2))$$

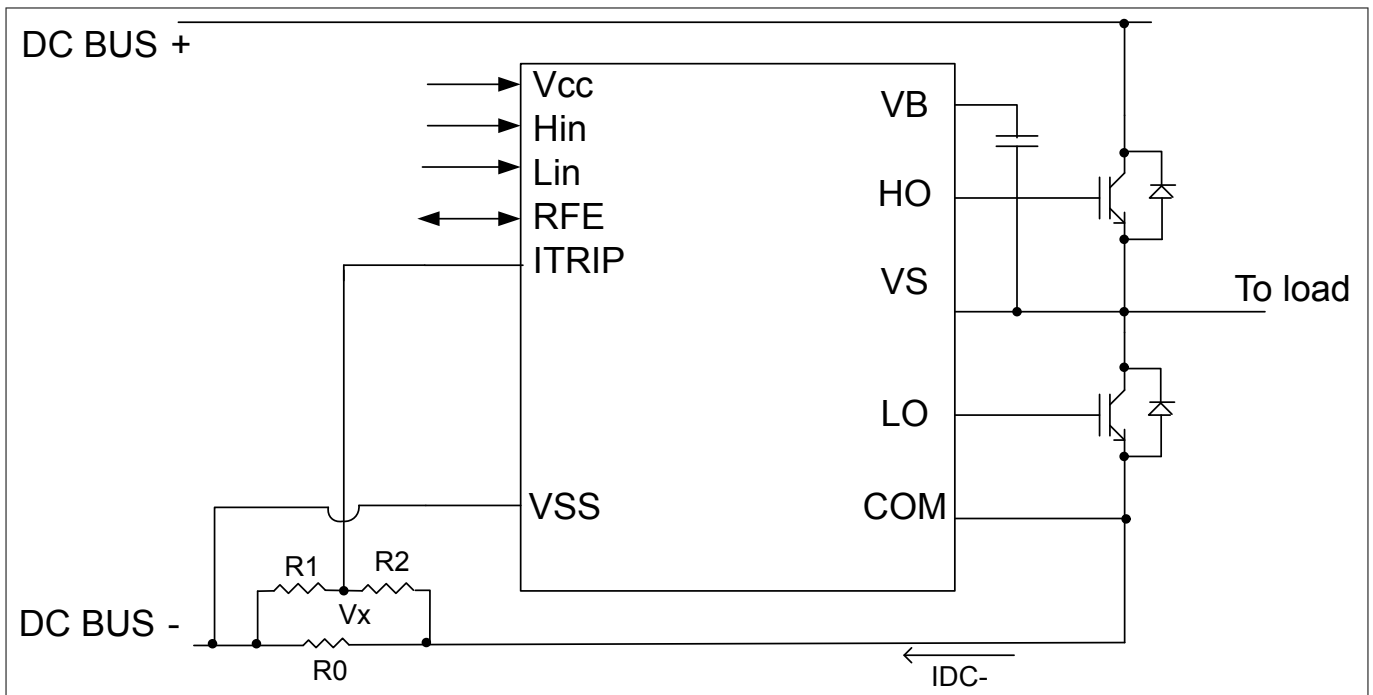


Figure 15 Programming the over-current protection

For example, a typical value for resistor R₀ could be 50 mΩ. The voltage of the ITRIP pin should not be allowed to exceed 5 V; if necessary, an external voltage clamp may be used.

6.9 Truth table: Undervoltage lockout, ITRIP, and ENABLE

Table 7 provides the truth table for the 6ED2230S12T. The first line shows that the UVLO for VCC has been tripped; the RFE output has gone low and the gate drive outputs have been disabled. VCCUV is not latched in this case and when VCC is greater than VCCUV, the FAULT output returns the driver is functional.

The second case shows that the UVLO for VBS has been tripped and that the high-side gate drive outputs have been disabled. After VBS exceeds the VBSUV threshold, HO will stay low until the HVIC input receives a new rising transition of HIN. The third case shows the normal operation of the HVIC. The fourth case illustrates that the ITRIP trip threshold has been reached and that the gate drive outputs have been disabled. This condition is stored in the external RC network waiting for fault clear time. The last case shows when the HVIC has received an enable command through the RFE input to shutdown; as a result, the gate drive outputs have been disabled.

Table 7 Truth table

	VCC	VBS	ITRIP	RFE	LO	HO
UVLO V _{CC}	<V _{CCUV}	—	—	0	0	0

Application information and additional details

Table 7 Truth table (continued)

	VCC	VBS	ITRIP	RFE	LO	HO
UVLO V_{BS}	15 V	$<V_{BSUV}$	0 V	HIGH	LIN	0
Normal operation	15 V	15 V	0 V	HIGH	LIN	HIN
ITRIP fault	15 V	15 V	$>V_{ITRIP+}$	0	0	0
Enable command	15 V	15 V	0 V	0	0	0

6.10 Advanced input filter

The advanced input filter allows an improvement in the input/output pulse symmetry of the HVIC and helps to reject noise spikes and short pulses. This input filter has been applied to the HIN and LIN inputs. The working principle of the new filter is shown in [Figure 17](#).

[Figure 16](#) shows a typical input filter and the asymmetry of the input and output. The upper pair of waveforms (Example 1) show an input signal with a duration much longer than $t_{FIL,IN}$; the resulting output is approximately the difference between the input signal and $t_{FIL,IN}$. The lower pair of waveforms (Example 2) show an input signal with a duration slightly longer than $t_{FIL,IN}$; the resulting output is approximately the difference between the input signal and $t_{FIL,IN}$.

[Figure 17](#) shows the advanced input filter of the 6ED2230S12T and the symmetry between the input and output. The upper pair of waveforms (Example 1) show an input signal with a duration much longer than $t_{FIL,IN}$; the resulting output is approximately the same duration as the input signal. The lower pair of waveforms (Example 2) show an input signal with a duration slightly longer than $t_{FIL,IN}$; the resulting output is approximately the same duration as the input signal.

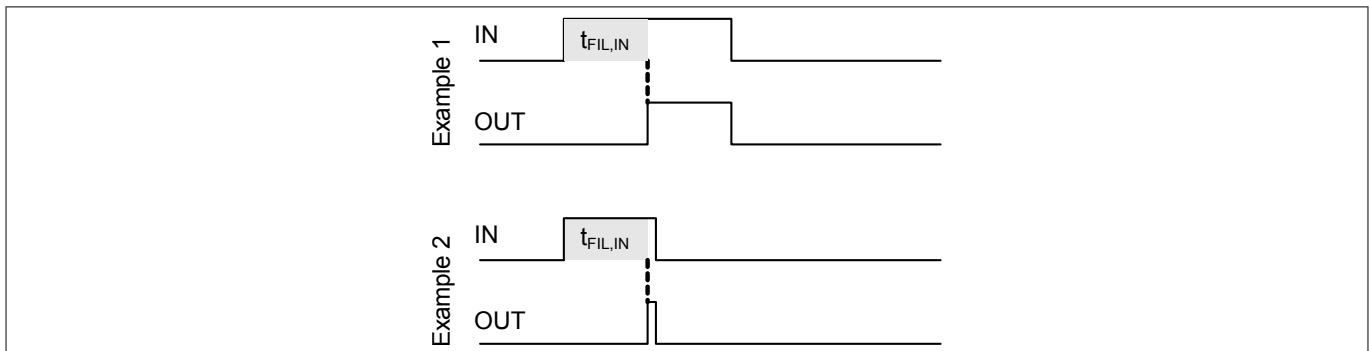


Figure 16 Typical input filter

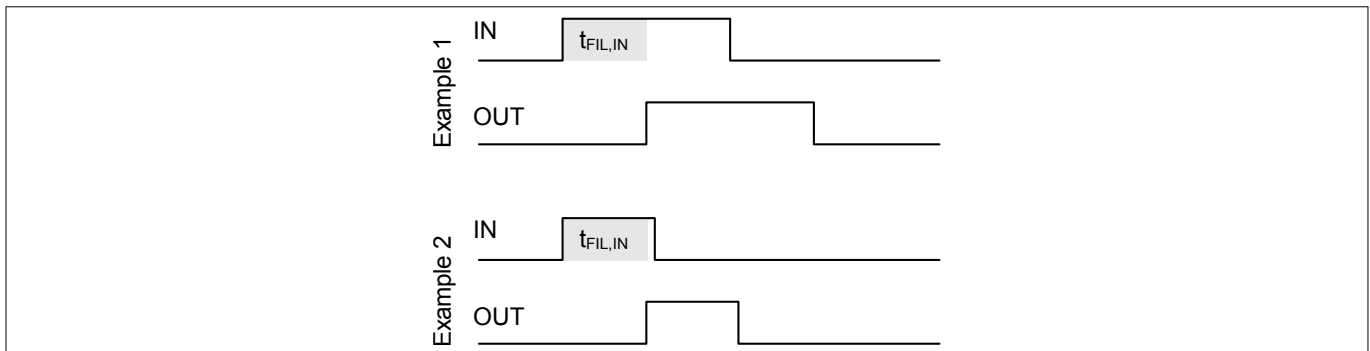


Figure 17 Advanced input filter

Application information and additional details

6.11 Short-Pulse / Noise rejection

This device's input filter provides protection against short-pulses (e.g., noise) on the input lines. If the duration of the input signal is less than $t_{FIL,IN}$, the output will not change states. Example 1 of [Figure 18](#) shows the input and output in the low state with positive noise spikes of durations less than $t_{FIL,IN}$; the output does not change states. Example 2 of [Figure 18](#) shows the input and output in the high state with negative noise spikes of durations less than $t_{FIL,IN}$; the output does not change states.

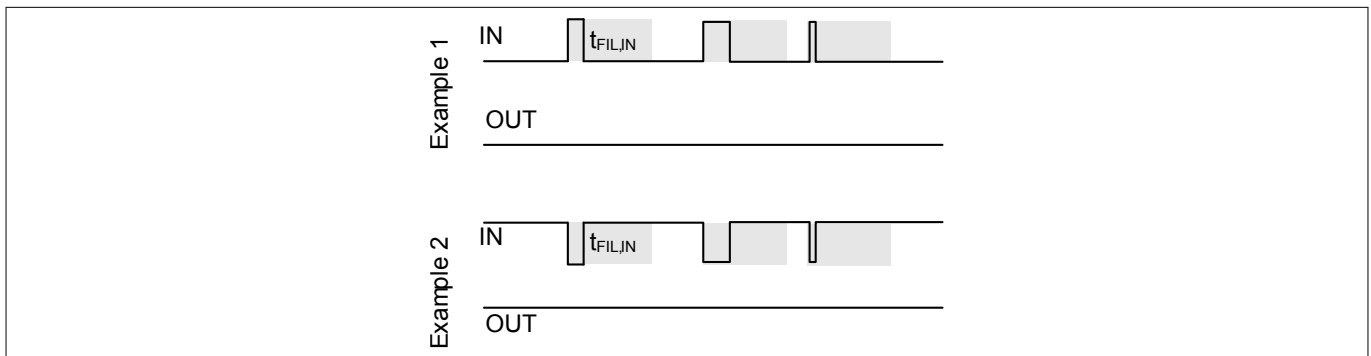


Figure 18 Noise rejecting input filters

6.12 Integrated bootstrap diodes

The 6ED2230S12T embeds three integrated ultra-fast bootstrap diodes that allow an alternative drive of the bootstrap supplies for a wide range of applications. The resistance of the diode (R_{BS}) helps to avoid high inrush currents when charging the bootstrap capacitance.

The bootstrap diode is connected between the floating supply V_B and V_{CC} (see [Figure 19](#)).

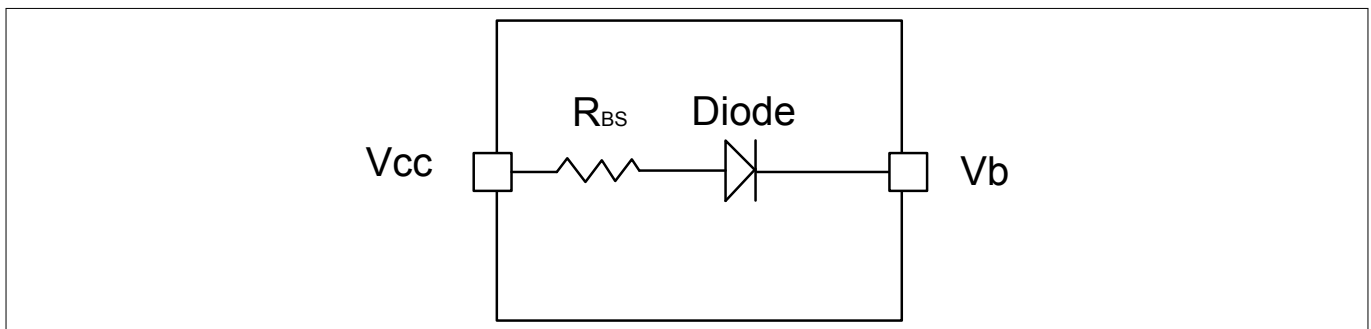


Figure 19 Simplified bootstrap diode connection

The bootstrap diode is suitable for all PWM modulation schemes, including trapezoidal control, and can be used either in parallel with the external bootstrap network (diode+ resistor) or as a replacement of it.

6.13 Tolerant to negative V_s transients

A common problem in today's high-power switching converters is the transient response of the switch node's voltage as the power switches transition on and off quickly while carrying a large current. A typical three phase inverter circuit is shown in [Figure 20](#); here we define the power switches and diodes of the inverter.

If the high-side switch (e.g., the IGBT Q1 in [Figure 21](#) and [Figure 22](#)) switches off, while the U phase current is flowing to an inductive load, a current commutation occurs from high-side switch (Q1) to the diode (D2) in parallel with the low-side switch of the same inverter leg. At the same instance, the voltage node V_{S1} , swings from the positive DC bus voltage to the negative DC bus voltage.

Application information and additional details

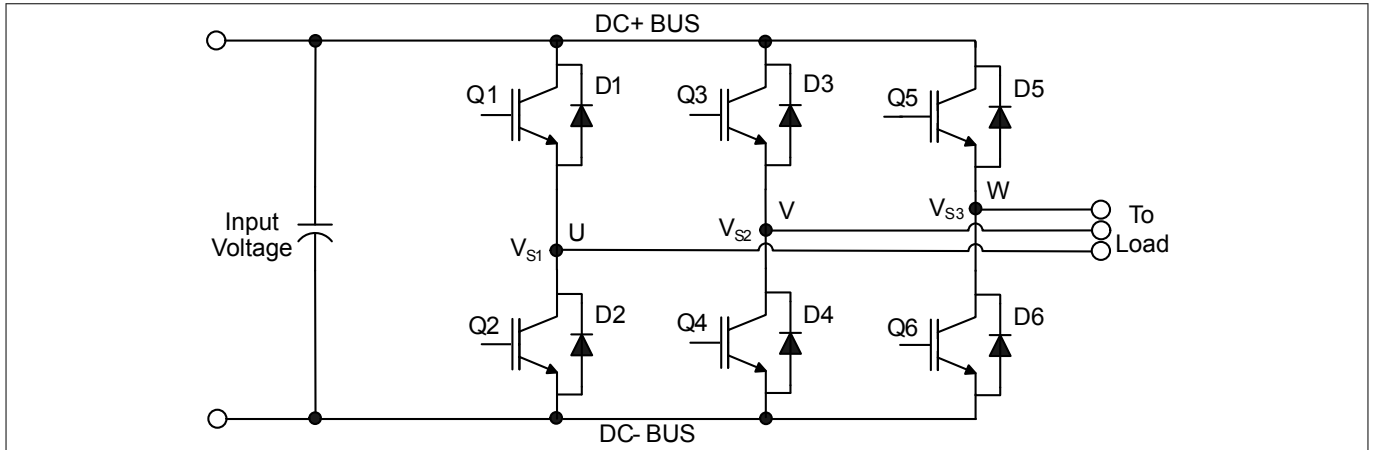


Figure 20 Three phase inverter

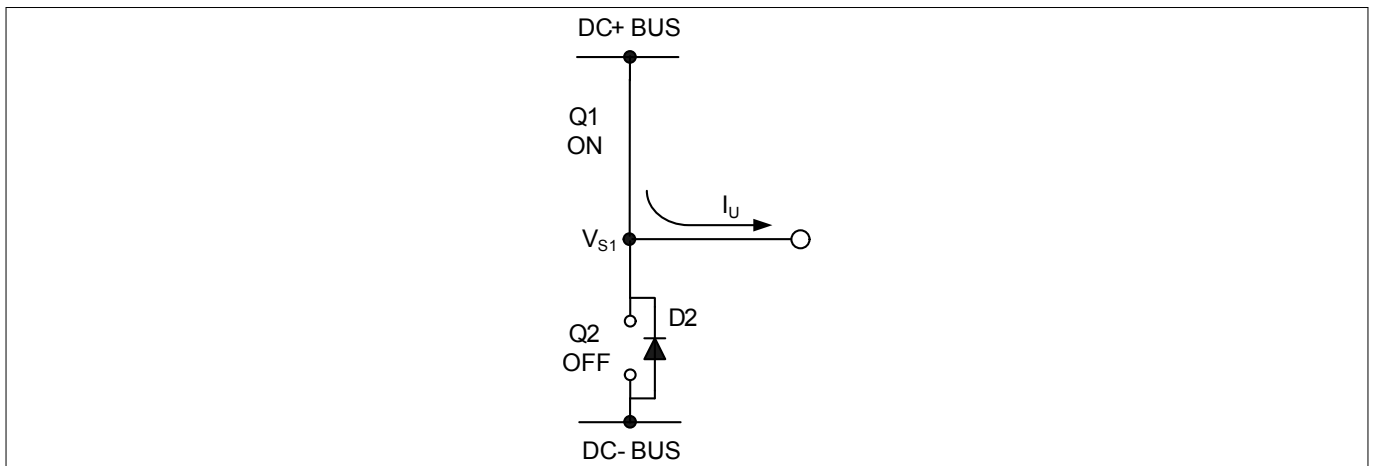


Figure 21 Q1 conducting

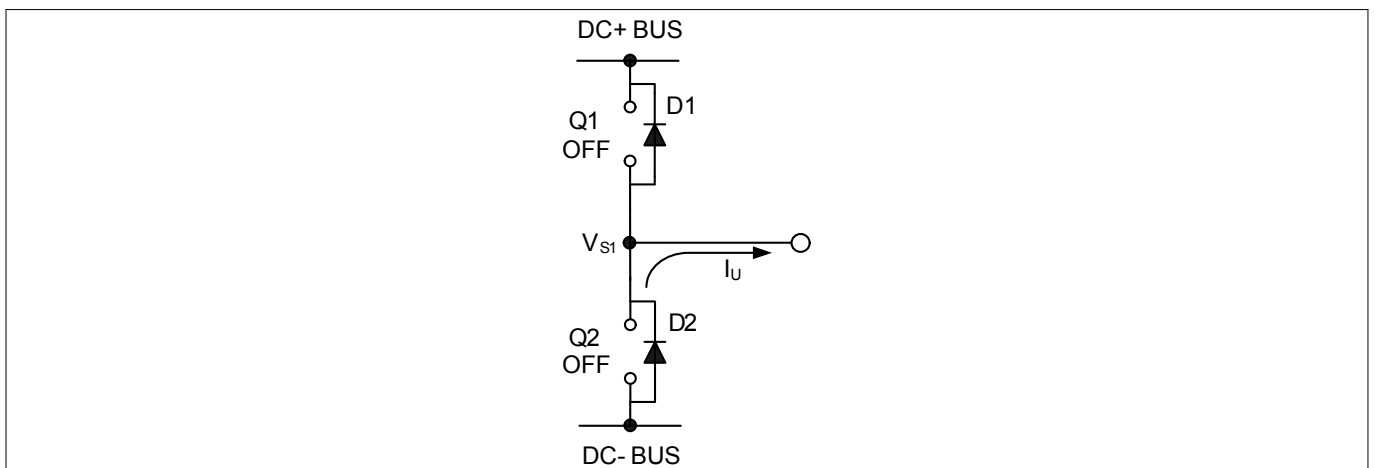


Figure 22 D2 conducting

Also when the V phase current flows from the inductive load back to the inverter (see [Figure 23](#) and [Figure 24](#)), and Q4 IGBT switches on, the current commutation occurs from D3 to Q4. At the same instance, the voltage node, VS2, swings from the positive DC bus voltage to the negative DC bus voltage.

Application information and additional details

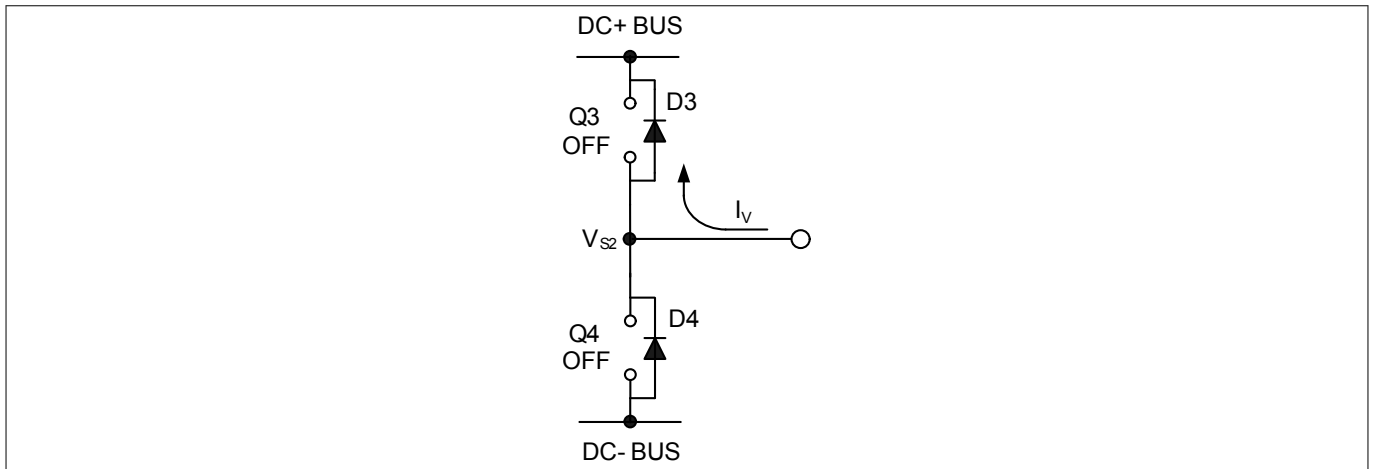


Figure 23 D3 conducting

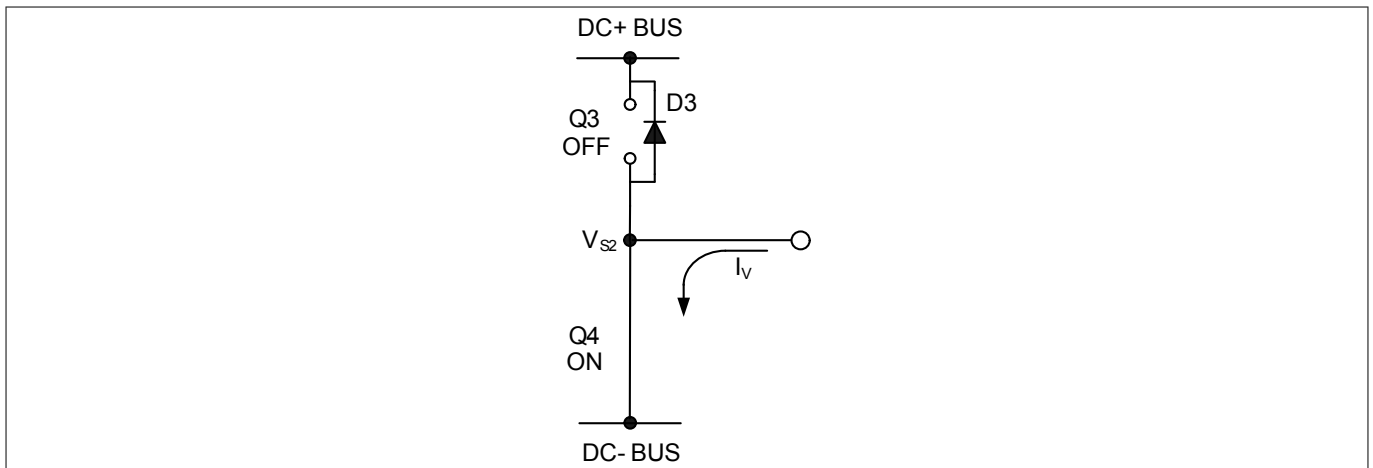


Figure 24 Q4 conducting

However, in a real inverter circuit the VS voltage swing does not stop at the level of the negative DC bus but instead swings below the level of the negative DC bus. This undershoot voltage is called “negative Vs transient”.

The circuit shown in [Figure 25](#) depicts one leg of the three phase inverter; [Figure 26](#) and [Figure 27](#) show a simplified illustration of the commutation of the current between Q1 and D2. The parasitic inductances in the power circuit from the die bonding to the PCB tracks are lumped together in LC and LE for each IGBT. When the high-side switch is on, VS1 is below the DC+ voltage by the voltage drops associated with the power switch and the parasitic elements of the circuit. When the high-side power switch turns off, the load current momentarily flows in the low-side freewheeling diode due to the inductive load connected to VS1 (the load is not shown in these figures). This current flows from the DC- bus (which is connected to the COM pin of the HVIC) to the load and a negative voltage between VS1 and the DC- Bus is induced (i.e., the COM pin of the HVIC is at a higher potential than the VS pin).

Application information and additional details

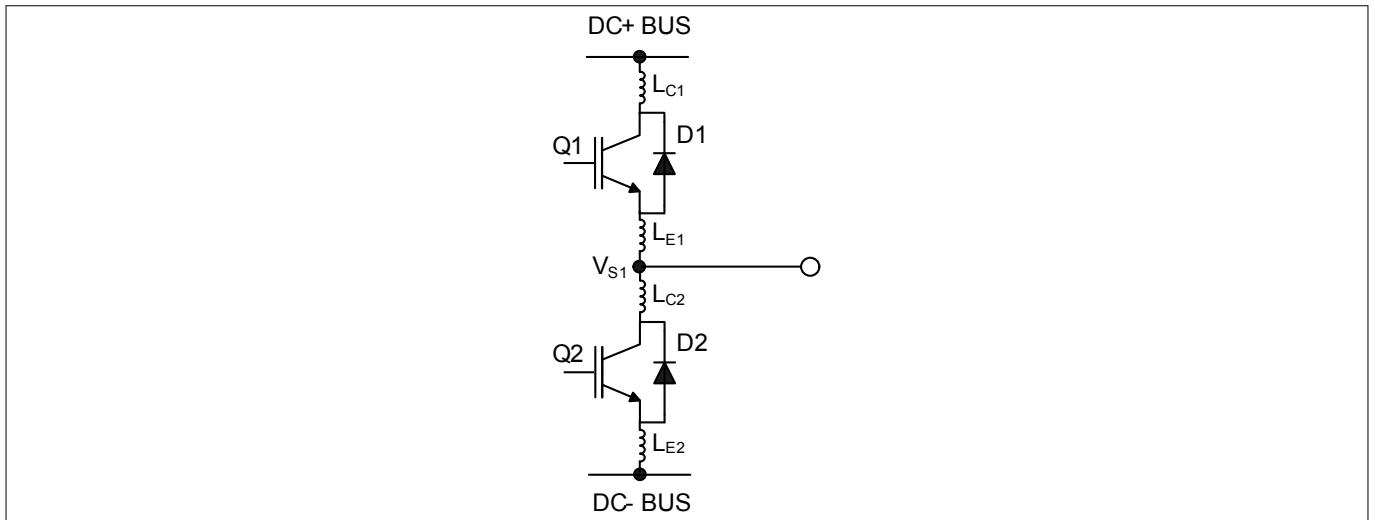


Figure 25 Parasitic elements

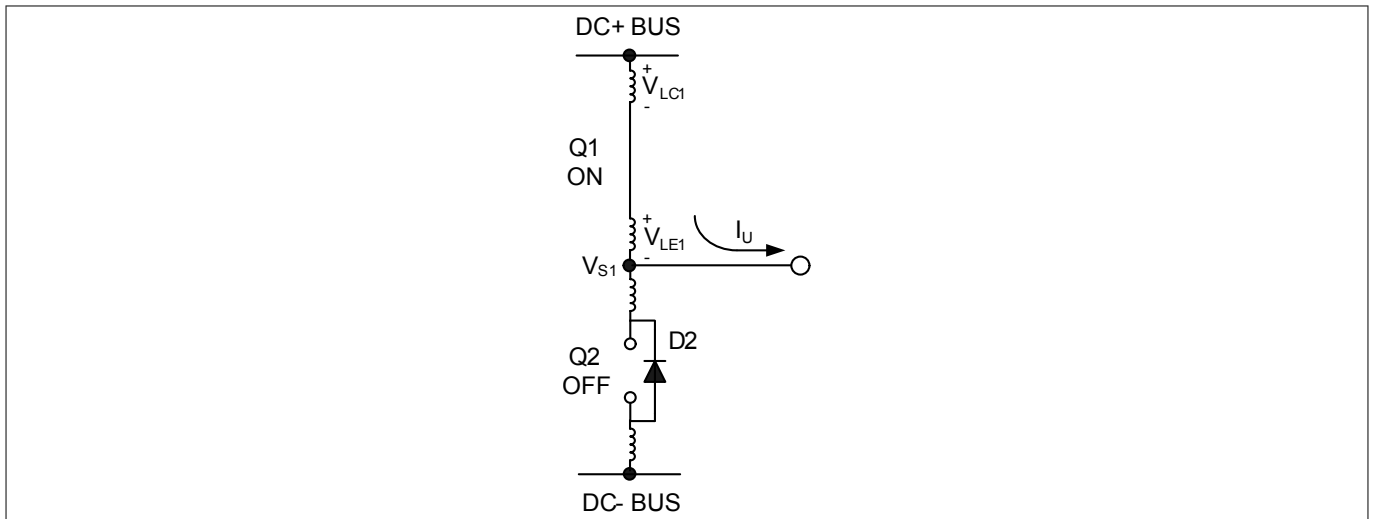


Figure 26 V_S positive

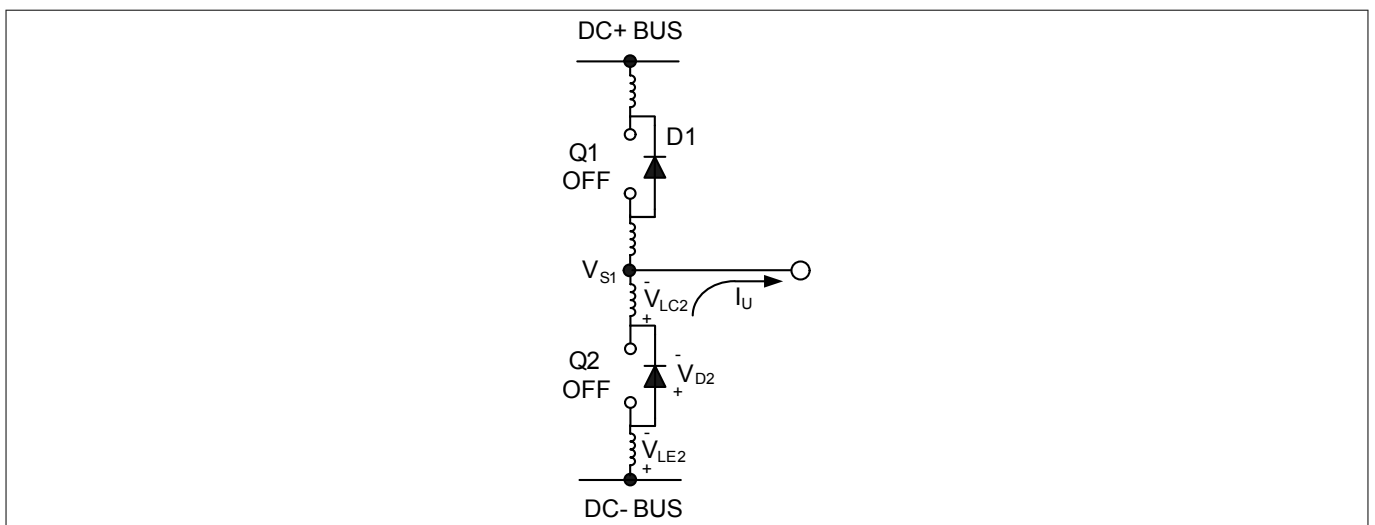


Figure 27 V_S negative

Application information and additional details

In a typical motor drive system, dV/dt is typically designed to be in the range of 3-5 V/ns. The negative V_s transient voltage can exceed this range during some events such as short circuit and over-current shutdown, when di/dt is greater than in normal operation.

Infineon's HVICs have been designed for the robustness required in many of today's demanding applications. An indication of the 6ED2230S12T's robustness can be seen in [Figure 28](#), where the 6ED2230S12T Safe Operating Area is shown at $V_{BS}=15V$ based on repetitive negative V_s spikes. A negative V_s transient voltage falling in the grey area (outside SOA) may lead to IC permanent damage; viceversa unwanted functional anomalies or permanent damage to the IC do not appear if negative V_s transients fall inside the SOA.

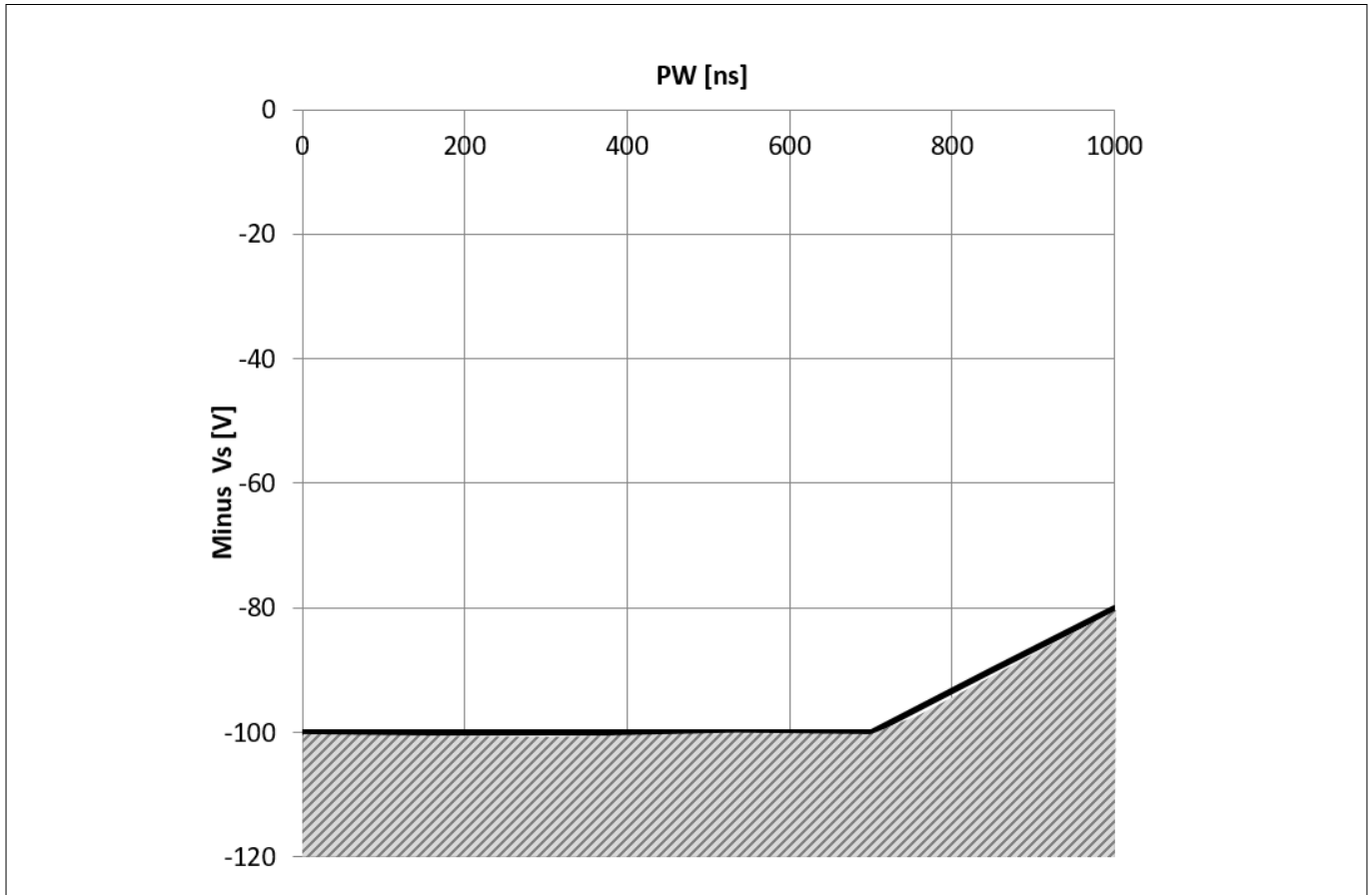


Figure 28 Negative V_s transient SOA for 6ED2230S12T @ $V_{BS}=15V$

Even though the 6ED2230S12T has been shown to be able to handle these large negative V_s transient conditions, it is highly recommended that the circuit designer always limit the negative V_s transients as much as possible by careful PCB layout and component use.

6.14 PCB layout tips

Distance between high and low voltage components: It's strongly recommended to place the components tied to the floating voltage pins (V_B and V_S) near the respective high voltage portions of the device. Please see the Case Outline information in this datasheet for the details.

Ground Plane: In order to minimize noise coupling, the ground plane should not be placed under or near the high voltage floating side.

Gate Drive Loops: Current loops behave like antennas and are able to receive and transmit EM noise (see [Figure 29](#)). In order to reduce the EM coupling and improve the power switch turn on/off performance, the gate drive loops must be reduced as much as possible. Moreover, current can be injected inside the gate drive loop via the IGBT collector-to-gate parasitic capacitance. The parasitic auto-inductance of the gate loop contributes to developing a voltage across the gate-emitter, thus increasing the possibility of a self turn-on effect.

Application information and additional details

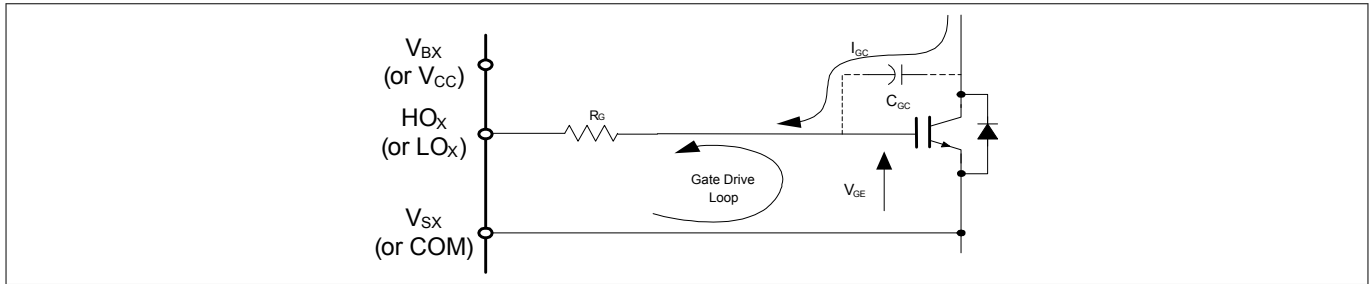


Figure 29 Antenna loops

Supply Capacitor: It is recommended to place a bypass capacitor (C_{IN}) between the V_{CC} and COM pins. A ceramic 1 μF ceramic capacitor is suitable for most applications. This component should be placed as close as possible to the pins in order to reduce parasitic elements.

Routing and Placement: Power stage PCB parasitic elements can contribute to large negative voltage transients at the switch node; it is recommended to limit the phase voltage negative transients. In order to avoid such conditions, it is recommended to 1) minimize the high-side emitter to low-side collector distance, and 2) minimize the low-side emitter to negative bus rail stray inductance. However, where negative V_s spikes remain excessive, further steps may be taken to reduce the spike. This includes placing a resistor (5 Ω or less) between the V_S pin and the switch node (see Figure 27), and in some cases using a clamping diode between COM and V_S (see Figure 31). See DT04-4 at <http://www.infineon.com> for more detailed information.

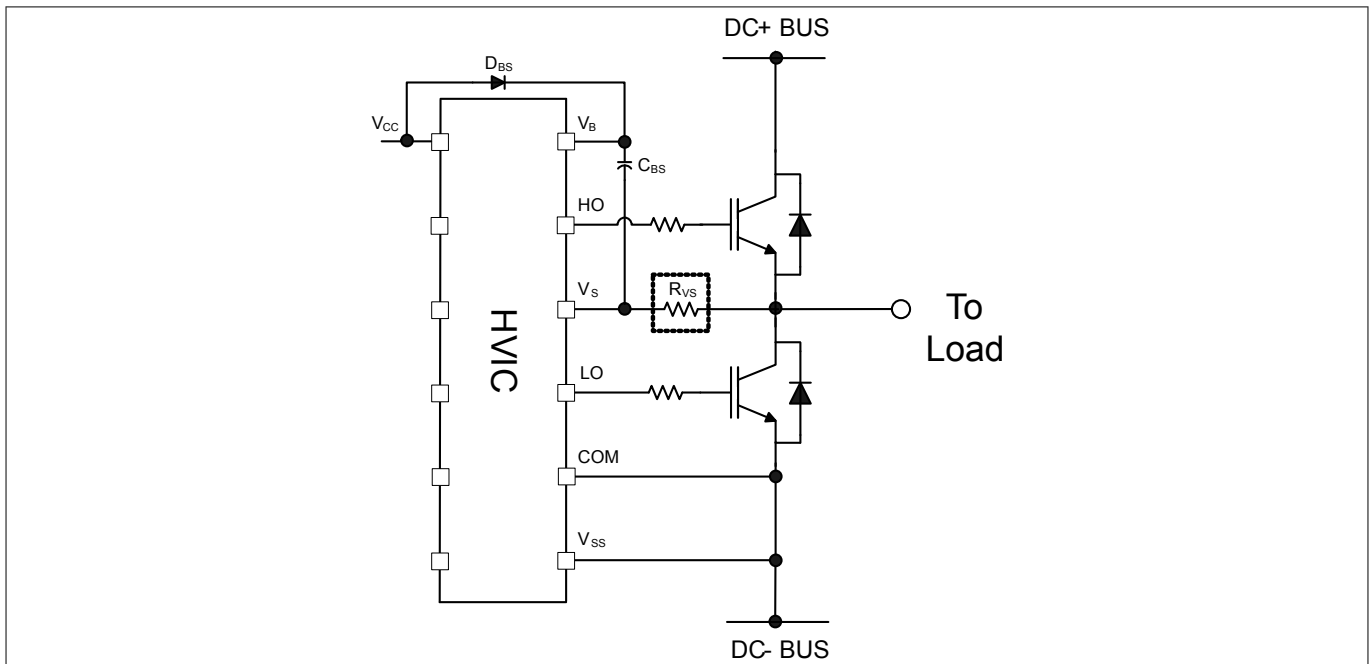


Figure 30 V_s resistor

Application information and additional details

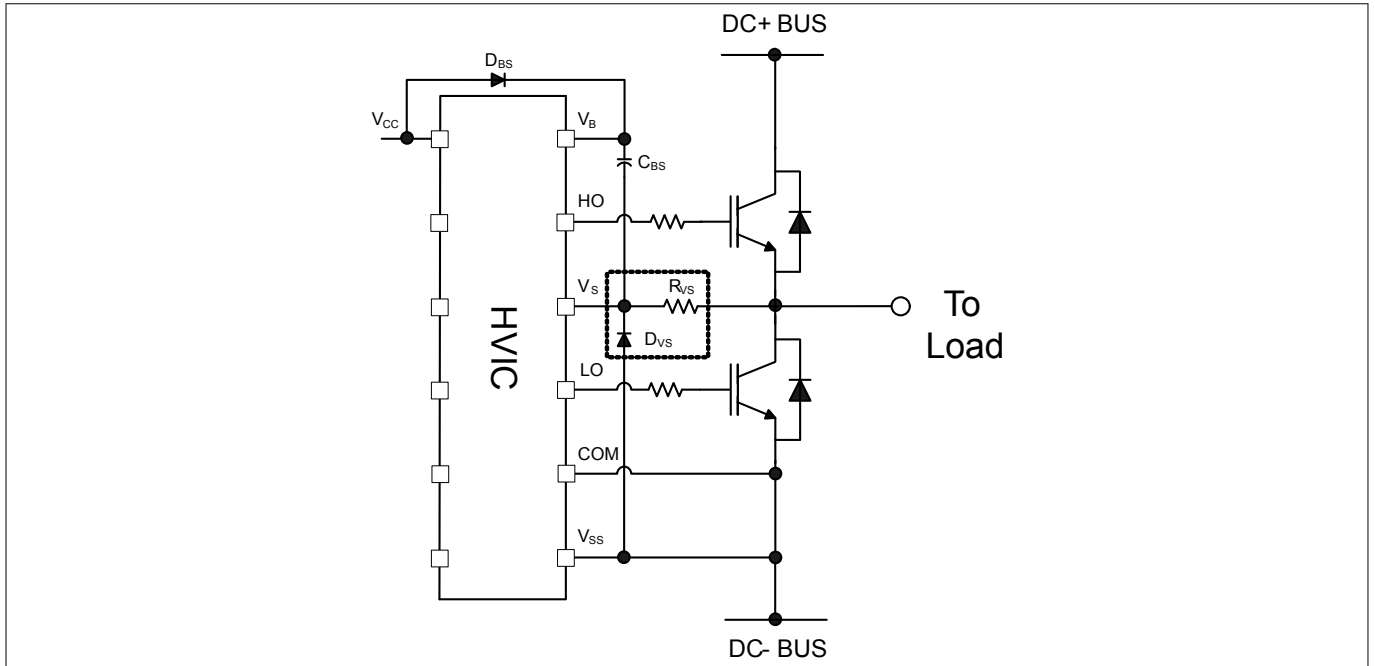


Figure 31 V_s clamping diode

6.15 Additional documentation

Several technical documents related to the use of HVICs are available at <http://www.infineon.com>; use the Site Search function and the document number to quickly locate them. Below is a short list of some of these documents.

DT97-3: Managing Transients in Control IC Driven Power Stages

AN-1123: Bootstrap Network Analysis: Focusing on the Integrated Bootstrap Functionality

DT04-4: Using Monolithic High Voltage Gate Drivers

AN-978: HV Floating MOS-Gate Driver ICs

Package information

7 Package information

7.1 Package information DSO-24 (DSO-28 4 pins removed)

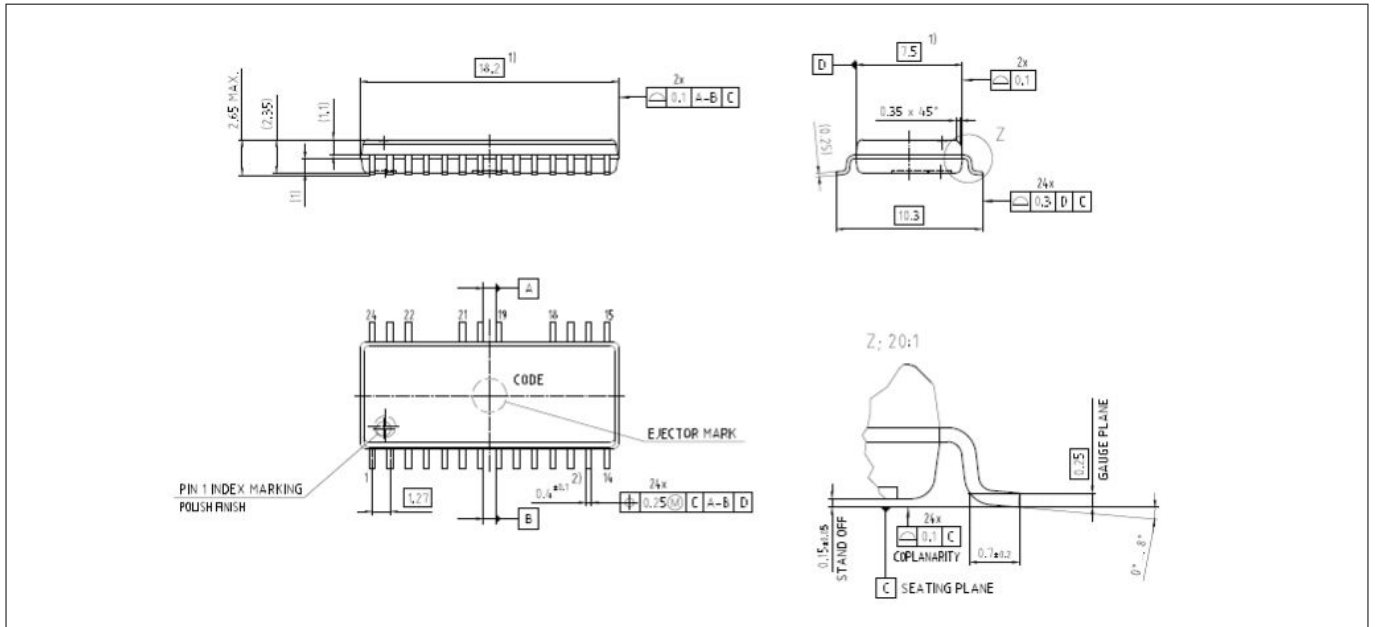


Figure 32 Package outline

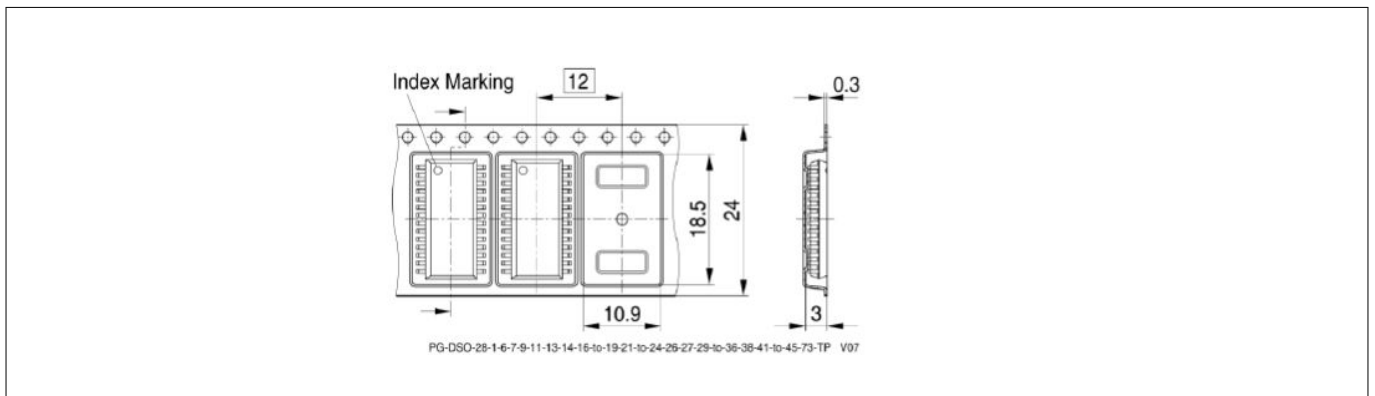


Figure 33 Tape and Reel details

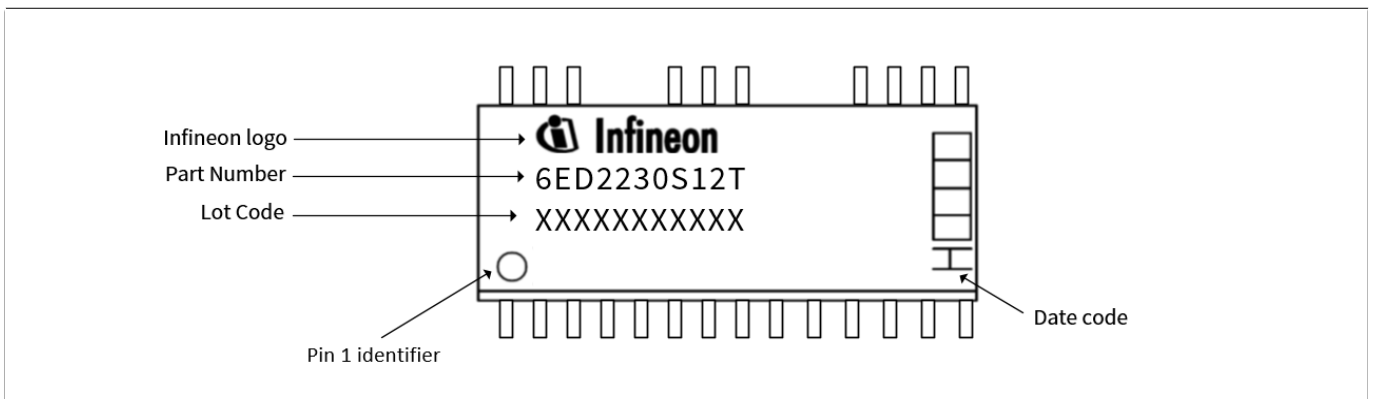


Figure 34 Marking information PG-DSO-24 (DSO-28 4 pins removed)

Qualification information

8 Qualification information

Table 8 Qualification information ¹⁾

Qualification Level		Industrial ²⁾	
		<i>Note: This family of ICs has passed JEDEC's Industrial qualification. Consumer qualification level is granted by extension of the higher Industrial level.</i>	
Moisture Sensitivity Level		DSO-24	MSL3 ³⁾ 260 °C (per IPC/JEDEC J-STD-020)
ESD	Human Body Model	Class 2 (per JEDEC standard JESD22-A114)	
	Charged Device Model	Class C4 (per JEDEC standard JS-022-2014)	
IC Latch-Up Test		Class II Level A (per JESD78)	
RoHS Compliant		Yes	

¹ Qualification standards can be found at Infineon's web site www.infineon.com

² Higher qualification ratings may be available should the user have such requirements. Please contact your Infineon sales representative for further information.

³ Higher MSL ratings may be available for the specific package types listed here. Please contact your Infineon sales representative for further information.

Related products

9 Related products

Table 9 Related products

Product	Description
Gate Driver ICs	
IR2214SS	1200 V Half-bridge gate driver with integrated dead-time, desaturation detection (DESAT), soft over-current shutdown, synchronized shutdown, two-stage turn-on for di/dt control, separate pull-up/pull-down output drive pins, matched propagation delays, and independent UVLO with hysteresis.
IR2213S	1200 V High and Low side gate driver with cycle by cycle shutdown logic, independent UVLO with hysteresis, matched propagation delays, and separate logic and power grounds.
IR2238Q	1200 V Three-phase motor controller with integrated programmable dead-time, desaturation detection (DESAT), brake chopper driver with protection, soft over-current shutdown, synchronized shutdown, hard shutdown, two-stage turn-on for di/dt control, separate pull-up/pull-down output drive pins, matched propagation delays, and independent UVLO with hysteresis.
Power Switches	
IKW15N120BH6 IKW40N120CS6	High Speed 1200 V, 15 A/40 A/75 A hard-switching TRENCHSTOP™ IGBT6 co-packed with a very soft and fast recovery anti-parallel diode in a TO247 package/TO247PLUS 3pin package
IKW08T120 IKW15N120T2 IKW25N120T2 IKW40N120T2	The 1200 V, 8 A/15 A/25 A/40 A hard-switching TRENCHSTOP™ IGBT3 co-packed with free-wheeling diode in a TO247 package, provides significant improvement of static as well as dynamic performance of the device, due to combination of trench-cell and fieldstop concept.
IKQ40N120CT2	Infineon introduces the new package TO-247PLUS for 1200 V IGBT with increasing amounts of silicon in smaller, space saving packages with 40 A/50 A/75 A.
Power Modules	
FP15R12W1T4 FP15R12W2T4 FP35R12W2T4	EasyPIM™ 1B/2B 1200 V, 15 A/35 A PIM IGBT module with fast Trench/Fieldstop IGBT4, Emitter Controlled 4 diode and NTC.
FP15R12W1T4_B11	EasyPIM™ 1B 1200 V, 15 A PIM IGBT module with fast Trench/Fieldstop IGBT4, Emitter Controlled 4 diode, NTC and PressFIT Contact Technology.
FS25R12W1T4 FS35R12W1T4	EasyPACK™ 1B 1200 V, 25 A/35 A sixpack IGBT module with Trench/Fieldstop IGBT4, Emitter Controlled 4 diode and NTC.
FS25R12W1T4_B11	EasyPACK™ 1B 1200 V, 25 A sixpack IGBT module with Trench/Fieldstop IGBT4, Emitter Controlled 4 diode, NTC and PressFIT Contact Technology.
iMOTION™ Controllers	
IRMCK099	iMOTION™ Motor control IC for variable speed drives utilizing sensor-less Field Oriented Control (FOC) for Permanent Magnet Synchronous Motors (PMSM).
IMC101T	High performance Motor Control IC for variable speed drives based on Field Oriented Control (FOC) of permanent magnet synchronous motors (PMSM).

Revision history

Revision history

Document version	Date of release	Description of changes
1.0	2018-03-27	First Release Version
1.1	2018-12-14	Update the ITRIP to output shutdown propagation delay Max. value
1.2	2019-08-05	Editorial change
1.3	2020-03-10	Editorial change

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